

| L Number | Hits | Search Text | DB | Time stamp |
|-------------|------|--|--------------------|---------------------|
| - | 2 | semiconductor ADJ device with wait ADJ time | USPAT | 2004/05/24 16:02 |
| - | 37 | semiconductor with wait ADJ time | USPAT | 2004/05/24 16:02 |
| - | 109 | semiconductor with wait\$3 ADJ time | USPAT | 2004/05/24 16:02 |
| - | 109 | semiconductor with wait\$3 ADJ time | USPAT | 2004/05/24 16:04 |
| - | 593 | semiconductor ADJ device AND wait\$3 ADJ time | USPAT | 2004/05/24 16:04 |
| - | 6 | semiconductor ADJ device AND wait\$3 ADJ time with elapse | USPAT | 2004/05/24 16:07 |
| - | 0 | 714/815.ccls. and semiconductor ADJ device AND wait\$3 ADJ time with elapse | USPAT | 2004/05/24 16:08 |
| - | 1 | 714/815.ccls. and semiconductor ADJ device AND wait\$3 ADJ time | USPAT | 2004/05/24 16:08 |
| - | 196 | 714/815.ccls. | USPAT | 2004/05/24 16:09 |
| - | 40 | 714/815.ccls. and (wait or delay) adj tim\$3 | USPAT | 2004/05/24 16:35 |
| - | 5 | 714/815.ccls. and (wait or delay) adj tim\$3 with measur\$5 | USPAT | 2004/05/24 16:37 |
| - | 1 | 714/815.ccls. and (wait or idle) adj tim\$3 with measur\$5 | USPAT | 2004/05/24 16:37 |
| - | 6 | 714/815.ccls. and wait adj tim\$3 | USPAT | 2004/05/24 16:41 |
| - | 287 | 714/\$.ccls. and wait adj tim\$3 | USPAT | 2004/05/24 16:41 |
| - | 287 | 714/\$.ccls. and wait adj tim\$3 | USPAT | 2004/05/24 16:44 |
| - | 3 | 714/\$.ccls. and wait adj tim\$3 with measur\$5 | USPAT | 2004/05/24 16:44 |
| - | 27 | 714/\$.ccls. and wait adj tim\$3 with test\$3 | USPAT | 2004/05/24 16:47 |
| - | 0 | 714/\$.ccls. and taet adj pattern and wait adj tim\$3 | USPAT | 2004/05/24 16:47 |
| - | 19 | 714/\$.ccls. and test adj pattern and wait adj tim\$3 | USPAT | 2004/05/24 16:57 |
| - | 188 | 714/\$.ccls. and test adj pattern and wait\$ with tim\$3 | USPAT | 2004/05/24 16:58 |
| - | 25 | 714/\$.ccls. and test adj pattern and wait\$ with tim\$3 and device adj under adj test | USPAT | 2004/05/24 17:50 |
| - | 160 | 714/\$.ccls. and test adj pattern and (wait\$ or delay) with tim\$3 and device adj under adj test | USPAT | 2004/05/24 18:11 |
| - | 31 | 714/\$.ccls. and test adj pattern and (wait\$ or delay) with tim\$3 with compar\$4 and device adj under adj test | USPAT | 2004/05/24 18:10 |
| - | 0 | 714/\$.ccls. and test adj pattern and variable ADJ time ADJ delay and device adj under adj test | USPAT | 2004/05/24 18:12 |
| - | 1 | 714/\$.ccls. and test adj pattern and variable ADJ time ADJ delay | USPAT | 2004/05/24 18:13 |
| - | 0 | 714/\$.ccls. and test adj pattern and variable ADJ wait\$3 ADJ time | USPAT | 2004/05/24 18:13 |
| - | 0 | 714/\$.ccls. and test adj pattern and adjustable with wait\$3 ADJ time | USPAT | 2004/05/24 18:13 |
| - | 0 | 714/\$.ccls. and test adj pattern and adjust\$3 with wait\$3 adj (tim\$3 or period) | USPAT | 2004/05/24 18:14 |
| - | 6 | 714/\$.ccls. and test adj pattern with wait\$3 adj (tim\$3 or period) | USPAT | 2004/05/24 18:16 |
| - | 17 | 714/\$.ccls. and test adj pattern with wait\$3 with (tim\$3 or period) | USPAT | 2004/05/24 18:28 |
| - | 0 | "20020100000" | USPAT | 2004/05/24 18:28 |
| - | 1 | "20020100000" | USPAT; US-PGPUB | 2004/05/24 18:28 |

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|---|-------|---|--------------------------------|---------------------|
| - | 383 | TOSHIBA.as. and wait\$3 adj tim\$3 | USPAT | 2004/05/24 18:43 |
| - | 28175 | TOSHIBA.as. and wait\$3 adj tim\$3 and test adj pattern and deviceADJ under adj test | USPAT | 2004/05/24 18:42 |
| - | 0 | TOSHIBA.as. and wait\$3 adj tim\$3 and test adj pattern and device ADJ under adj test | USPAT | 2004/05/24 18:43 |
| - | 1 | TOSHIBA.as. and wait\$3 adj tim\$3 and device ADJ under adj test | USPAT | 2004/05/24 18:43 |
| - | 0 | TOSHIBA.as. and wait\$3 adj tim\$3 with semiconductor adj test\$3 | USPAT | 2004/05/24 18:44 |
| - | 0 | TOSHIBA.as. and wait\$3 adj tim\$3 and semiconductor adj test\$3 | USPAT | 2004/05/24 18:46 |
| - | 1 | JP08247817 | USPAT; EPO; JPO; DERWENT | 2004/05/25 07:50 |
| - | 1 | JP08247817 | USPAT; EPO; JPO; DERWENT | 2004/05/25 07:50 |
| - | 1 | measurement with adjust\$4 with operating with speed and TESTING with SEMICONDUCTOR near DEVICE | USPAT | 2004/05/25 07:52 |
| - | 1 | measurement with adjust\$4 with speed and TESTING with SEMICONDUCTOR near DEVICE | USPAT | 2004/05/25 07:53 |
| - | 19 | adjust\$4 with speed and TESTING with SEMICONDUCTOR near DEVICE | USPAT | 2004/05/25 07:57 |
| - | 36 | adjust\$4 with time with delay and TESTING with SEMICONDUCTOR near DEVICE | USPAT | 2004/05/25 07:57 |
| - | 34 | 714/815.ccls. and (wait or delay) adj time | USPAT | 2004/05/25 15:59 |